## Application/Control No. Applicant(s)/Patent Under Reexamination 10/082,081 LEE, CHULHEE Notice of References Cited Art Unit Examiner Page 1 of 1 2621 Dave Czekaj **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY \* US-6,049,630 04-2000 Wang et al. 382/239 Α \* 348/390.1 US-5,841,473 11-1998 Chui et al. В US-Ç US-D US-E US-F US-G US-Н US-1 US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Date **Document Number** Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS**

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